19. (Amended) A semiconductor device as claimed in claim 13 or 14, wherein said circuit comprising the switch elements is a clock circuit or a flip-flop circuit.

20. (Amended) A semiconductor device as claimed in claim 13 or 14, wherein said switch elements are formed of field effect transistors in said basic cells.

21. (Amended) A semiconductor device as claimed in any one of claims 7 to 14, wherein said basic cells include the p-channel type field effect transistors and n-channel type field effect transistors.

22. (Amended) A semiconductor device as claimed in any one of claims 7 to 12, wherein a wiring electrically connected to the gate electrode of said switch element is formed of the wiring of the third wiring layer and this wiring is arranged in parallel to said power supply wirings.

23. (Amended) A semiconductor device as claimed in any one of claims 7 to 14, wherein a semiconductor region for power feeding to supply the predetermined voltage to the semiconductor region formed in said semiconductor substrate is formed in the region between the internal circuit region where a plurality of said basic cells are arranged and the peripheral circuit region at the external side of said internal circuit region.

(Amended) A semiconductor device as claimed in any one of claims I to 14, wherein said switch elements are turned ON in the normal operation period of semiconductor device and the power supply voltage is applied from said power supply wirings to the semiconductor region formed in said semiconductor substrate and said switch elements are turned OFF in the testing or waiting period of semiconductor device and the voltage different from said power supply voltage is applied to said semiconductor region.

Sub (33)

37. (Amended) A semiconductor device as claimed in claim 33, 34 or 35, wherein the wiring connected to the gate electrode of the field effect transistor forming said switch element is arranged to surround the internal circuit region of a semiconductor device.

38. (Amended) A semiconductor device as claimed in any one of claims 33 to 35, wherein at least one of a pair of semiconductor regions for source and drain of the field effect transistors unused for said input/output circuits is electrically connected to said power supply wiring to form a capacitance element.

A semiconductor device as claimed in any one of claims 7 to 12, wherein a logic circuit is formed using said basic cells and said logic circuit is formed among the basic cells forming said switch element.

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46. A semiconductor device claimed in claim 9, 11,

or 12; wherein a logic circuit is formed using said basic cells, said unused field effect transistor is the field effect transistor of basic cell not forming a logic circuit and said logic circuit and unused basic cells are formed among the basic cells forming said switch element.